ABSOLUTE MAXIMUM RATINGS (Note 1)

Operating Temperature Range	,
MUX-08/24-AQ, BQ, BRC	55°C to +125°C
MUX-02/24-EQ, FQ	25°C to +85°C
MUX-08/24-EP	0°C to +70°C
MUX-08/24-FP, FS	40°C to +85°C
Junction Temperature (T _j) Storage Temperature Range	65°C to +150°C
Storage Temperature Range	65°C to +150°C
P-Suffix	65°C to +125°C
Lead Temperature (Soldering, 60 sec)	300°C
Maximum Junction Temperature	150°C
V+ Supply to V- Supply	36V
Logic Input Voltage (-4V	or V-) to V+ Supply

Analog Input Voltage	V- Supply -20	V to V+ Su	pply +20V
Maximum Current Thro	ugh Any Pin		25mA
PACKAGE TYPE	⊖ _{jA} (Note 2)	Θ _{jC}	UNITS
16-Pin Hermetic DIP (Q)	100	16	.cw
16-Pin Plastic DIP (P)	82	39	°C/W
20-Contact LCC (RC)	98	38	°C/W
16-Pin SO (S)	111	35	°C/W

NOTES:

- 1. Absolute maximum ratings apply to both DICE and packaged parts, unless
- Absolute inaximitatings apply to both Diot. and packaged parts, unless otherwise noted.
 ⊕_{jA} is specified for worst case mounting conditions, i.e., ⊕_{jA} is specified for device in socket for CerDIP, P-DIP, and LCC packages; ⊕_{jA} is specified for device soldered to printed circuit board for SO package.

ELECTRICAL CHARACTERISTICS at V+ = +15V, V- = -15V and T_A = 25°C, unless otherwise noted.

				MUX-08A/E		MUX-08B/F				
PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNITS
"ON" Resistance	R _{ON}	$V_S \le 10V, I_S \le 200 \mu A$		_	220	300	_	300	400	Ω
ΔR _{ON} With Applied Voltage	ΔR_{ON}	$-10V \le V_S \le 10V$, $I_S = 200 \mu A$			1	5	_	3	7	%
R _{ON} Match Between Switches	R _{ON} Match	$V_S = 0V$, $I_S = 200 \mu A$		_	7	15	_	9	20	%
Analog Voltage Range	V_A	(Note 6)		+10 -10	+10.4 -15	_	+10 -10	+10.4 -15	_	V
Source Current (Switch "OFF")	Is (OFF)	$V_S = 10V, V_D = -10V \text{ (Note 1)}$			0.01	1.0		0.01	2.0	nA
Drain Current (Switch "OFF")	I _{D (OFF)}	$V_S = 10V, V_D = -10V \text{ (Note 1)}$	MUX-08 MUX-24	_	0.1 0.05	1.0 1.0	_	0.1 0.05	2.0 2.0	nA
Leakage Current (Switch "ON")	I _{D (ON)} +I _{S (ON)}	V _D = 10V (Note 1)	MUX-08 MUX-24	_	0.1 0.05	1.0 1.0	<u>-</u> -	0.1 0.05	2.0 2.0	nA
Digital Input Current	I _{IN}	$V_{IN} = 0.4V \text{ to } 15V$		_	1	10	_	1	10	μΑ
Digital "0" Enable Current	I _{INL (EN)}	V _{EN} = 0.4V		_	4	10	_	4	10	μΑ
Digital Input Capacitance	C _{DIG}			_	3	_	_	3		pF
Switching Time (t _{TRAN})	t _{PHL} t _{PLH}	(Notes 2, 5) Figure 1 (Test Circuit)		_	1.5 1.0	2.1 1.3		1.5 1.0	2.1 1.3	μs
Output Settling Time	t _S	10V Step to 0.10% 10V Step to 0.05% 10V Step to 0.02%			2.2 2.7 3.4	_ 	_ _ _	2.2 2.7 3.4	_ _ _	μs
Break-Before-Make Delay	t _{OPEN}	Figure 3 (Test Circuit)		_	0.8	-	_	1.0	_	μS
Enable Delay "ON"	t _{ON (EN)}	(Note 5) Figure 2 (Test Circuit)		_	1	2	_	1	2	μs
Enable Delay "OFF"	t _{OFF (EN)}	(Note 5) Figure 2 (Test Circuit)	MUX-08 MUX-24		0.1 0.2	0.4 0.5	_	0.2	0.4 0.6	μs
"OFF" Isolation	ISO _{OFF}	(Note 4) Figure 5 (Test Circuit)	MUX-08 MUX-24	_	60 66	_	_	60 66		dB
Crosstalk	СТ	(Note 3) Figure 4 (Test Circuit)	MUX-08 MUX-24	_	70 76			70 76		dB
Source Capacitance	C _{S (OFF)}	Switch "OFF", $V_S = 0V$, $V_D = 0V$	MUX-08 MUX-24	_	2.5 2	_	_	2.5		pF
Drain Capacitance	C _{D(OFF)}	Switch "OFF", V _S = 0V, V _D = 0V	MUX-08 MUX-24	_	7 4		_	7	_	pF
Input to Output Capacitance	C _{DS(OFF)}	(Note 4)	MUX-08 MUX-24	_	0.3 0.15		_	0.3 0.15		pF
Positive Supply Current (All Digital Inputs Logic "0" or "1")	I+	V+= 15V V+= 5V			10 8	12 —		6 5	12 —	mA
Negative Supply Current (All Digital Inputs Logic "0" or "1")	1	V+=-15V V+=-5V		_	3.0 2.5	3.8	_	2.0 1.8	3.8	mA

ELECTRICAL CHARACTERISTICS at V + = 15V, V - = -15V and -55° C $\leq T_A \leq 125^{\circ}$ C, unless otherwise noted.

	11			MUX-08A		MUX-08B				
PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNITS
"ON" Resistance	R _{ON}	$V_{S} \le 10V, I_{S} \le 200 \mu A$			_	425	_	_	500	Ω
ΔR _{ON} With Applied Voltage	ΔR _{ON}	$-10V \le V_S \le 10V$, $I_S = 200 \mu A$		_	1.5	_	_	4.5		. %
R _{ON} Match Between Switches	R _{ON} Match	$V_S = 0V, I_S = 200 \mu A$		_	10	_	_	15	_	%
Analog Voltage Range	V _A	(Note 6)		+10 -10	+ 10.4 -15	_	+10 -10	+ 10.4 -15	_	٧
Source Current (Switch "OFF")	I _{S (OFF)}	$V_S = 10V$, $V_D = -10V$ (Notes 1,	7)	_	_	25	_	_	50	nA
Drain Current (Switch "OFF")	I _{D (OFF)}	V _S = 10V, V _D = -10V (Notes 1, 7)	MUX-08 MUX-24	_	_	100 50		_	500 500	nA
Leakage Current (Switch "ON")	I _{D (ON)} +I _{S (ON)}	V _D = 10V (Notes 1, 7)	MUX-08 MUX-24	_	_	100 50	_	_	500 500	nA
Digital "1" Input Voltage	V _{INH}	(Note 6)		2			2			ν
Digital "0" Input Voltage	V _{INL}	(Note 6)		_		0.7	_	_	0.7	٧
Digital Input Current	I _{IN}	V _{IN} = 0.4V to 15V		_	_	20	-		20	μΑ
Digital "0" Enable Current	I _{INL (EN)}	V _{EN} = 0.4V		_	.—	20		_	20	μΑ
Positive Supply Current	1+	All Digital Inputs Logic "0" or "1"		_	_	15	_	_	15	mA
Negative Supply Current	I –	All Digital Inputs Logic "0" or "1"		_	_	5			5	mA

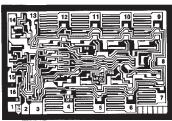
ELECTRICAL CHARACTERISTICS at V+ = 15V, V- = -15V and -25°C \leq T_A +85°C for MUX-08EQ/FQ and MUX-24EQ/FQ 0°C \leq T_A \leq +70°C for MUX-08EP and MUX-24EP; -40°C \leq T_A \leq +85°C for MUX-08FP/FS and MUX-24FP/FS, unless otherwise noted

				MUX-0		MUX-08E		UX-08	BF	
PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNITS
"ON" Resistance	R _{ON}	$V_{S} \le 10V, I_{\tilde{S}} \le 200 \mu A$			_	400	_	_	500	Ω
ΔR_{ON} With Applied Voltage	ΔR_{ON}	$-10V \le V_S \le 10V$, $I_S = 200 \mu A$		_	1.5	_	_	4.5		%
R _{ON} Match Between Switches	R _{ON} Match	$V_{S} = 0V, I_{S} = 200\mu A$		_	10	_	_	15	_	%
Analog Voltage Range	V _A	(Note 6)		+10 -10	+ 10.4 - 15	_	+10 -10	+ 10.4 - 15	_	٧
Source Current (Switch "OFF")	I _{S (OFF)}	$V_S = 10V$, $V_D = -10V$ (Notes 1,	7)	_	_	10	_		10	nA
Drain Current (Switch "OFF")	I _{D (OFF)}	$V_S = 10V, V_D = 10V$ (Notes 1, 7)	MUX-08 MUX-24		-	100 50	_	_	100 50	nA
Leakage Current (Switch "ON")	I _{D (ON)} +I _{S (ON)}	V _D = 10V (Notes 1, 7)	MUX-08 MUX-24	_	_	100 50	_	_	100 50	nA
Digital "1" Input Voltage	V _{INH}	(Note 6)		2			2	_	_	V
Digital "0" Input Voltage	V _{INL}	(Note 6)			_	8.0		_	0.8	V
Digital Input Current	L _{IN}	V _{IN} = 0.4V to 15V		_	-	20	_	_	20	μΑ
Digital "0" Enable Current	I _{INL (EN)}	V _{EN} = 0.4V		_		20			20	μΑ
Positive Supply Current	I+	All Digital Inputs Logic "0" or "1"			_	15	_		15	mA
Negative Supply Current	-	All Digital Inputs Logic "0" or "1"		_		5	_	_	5	mA

NOTES

- Conditions applied to leakage tests insure worst case leakages. Exceeding 11V on the analog input may cause an "OFF" channel to turn "ON".
- $2. \quad R_L = 10 M \Omega, \, C_L = 10 \rho F.$
- 3. Crosstalk is measured by driving channel 8 with channel 4 "ON". $\rm R_L=1M\Omega,\, C_L=10pF,\, V_S=5V$ RMS, f=500kHz.
- 4. "OFF" isolation is measured by driving channel 8 with ALL channels "OFF". R_L = $1k\Omega$, C_L = 10pF, V_S = 5V RMS, f = 500kHz. C_{DS} is computed from the OFF isolation measurement.
- 5. Sample tested.
- 6. Guaranteed by leakage current and $R_{\mbox{\scriptsize ON}}$ tests.
- 7. Leakage tests are performed only on military temperature grades at 125° C.

DICE CHARACTERISTICS (125°C TESTED DICE AVAILABLE)



MUX-08

DIE SIZE 0.093×0.059 inch, 5487 sq. mil (2.362 \times 1.500 mm, 3543 sq. mm)

9. S8 1. A0 2. ENABLE 10. S7 3. V-(SUBSTRATE) 11. \$6 12. S5 4. S1 5. S2 13. V+ 14. GND 6. \$3 15. A2 7. S4 8. DRAIN 16. A1

WAFER TEST LIMITS at V+=15V, V-=-15V, $T_A=25^{\circ}C$, unless otherwise noted. (Note 1)

				MUX-08/ MUX-24NT	MUX-08/ MUX-24N	MUX-08/ MUX-24G	
PARAMETER	SYMBOL	CONDITIONS		LIMIT	LIMIT	LIMIT	UNITS
"ON" Resistance	R _{ON}	$V_S = 0V$, $I_S = 200\mu A$	T _A = 125°C	300 400	300	400	Ω ΜΑΧ
Digital "1" Input Voltage	V _{INH}	(Note 2)		2	2	2	V MIN
Digital "0" Input Voltage	V _{INL}	(Note 2)		0.8	0.8	0.8	V MAX
Digital "0" Input Current	INL	V _{IN} = 0.4V	T _A = 125°C	10 20	10	10	μΑ MAX
Digital "0" Enable Current	I _{INL(EN)}	V _{IN} = 0.4V	T _A = 125°C	10 20	10	10	μΑ ΜΑΧ
Positive Supply Current (All Digital Inputs Logic "0")	1+		T _A = 125°C	12 15	12 —	12	mA MAX
Negative Supply Current (All Digital Inputs Logic "0")	-		T _A = 125°C	3.8 5	3.8	3.8	mA MAX
Analog Input Range	V _A	(Note 2)		±10	± 10	±10	V MIN

NOTE:

Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly mehtods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

TYPICAL ELECTRICAL CHARACTERISTICS at V+=15V, V-=-15V and $T_A=25^{\circ}$ C for MUX-08/24N & G, $T_A=125^{\circ}$ C for MUX-08/24NT, unless otherwise noted.

			MUX-08/	MUX-08/	MUX-08/	
PARAMETER	SYMBOL	CONDITIONS	MUX-24NT TYPICAL	MUX-24N TYPICAL	MUX-24G TYPICAL	UNITS
Switching Time (t _{TRAN})	t _{PHL} t _{PLH}	(Note 1)	1.7 1.1	1.3 0.9	2.1 1.3	μs
Output Settling Time	t _S	10V Step to 0.1% (Note 1)	2.1	1.5	1.9	μS
Break-Before-Make Delay	t _{OPEN}	(Note 1)	0.8	0.8	1.0	μS
Crosstalk	СТ	(Note 1)	70	70	70	dB
ΔR _{ON} With Applied Voltage	ΔR _{ON}	$-10V \le V_{S} \le 10V$, $I_{S} = 200 \mu A$	2	2	6	%
Leakage Current (Switch "ON")	I _{D(ON)}	V _D = 10V (Note 1)	20	0.5	0.5	nA
Analog Input Range	V _A		+10.4/-15	+ 10.4/-15	+ 10.4/- 15	٧

NOTES:

The data shown is extrapolated from measurements made on the packaged devices.

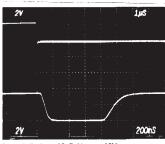
^{2.} Guaranteed by leakage current and $\rm R_{ON}\, tests.$

MUX-08 LOGIC STATE

A ₂	A ₁	A ₀	EN	"ON" CHANNEL
Х	Х	Х	L	NONE
L	L	L	Н	1
L	L	Н	Н	2
L	Н	L	Н	3
L	Н	Н	Н	4
Н	L	L	Н	5
Н	L	Н	Н	6
Н	Н	L	Н	7.
Н	Н	Н	Н	8

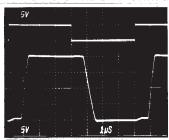
TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

MUX-08 BREAK-BEFORE-MAKE SWITCHING



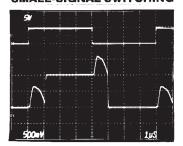
 $R_L = 1k\Omega$, $C_L = 10pF$, $V_{1, 8} = 10V$ VOLTAGE = 2V/DIVTIME = 200ns/DIV

MUX-08 LARGE-SIGNAL SWITCHING



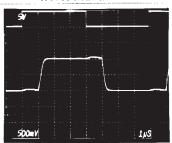
 $\overline{R_L}$ = 1M Ω , $\overline{C_L}$ = 10pF, V_1 = -10V, V_8 = +10V VOLTAGE = 5V/DIV TIME = 1 μ s/DIV

MUX-08 SMALL-SIGNAL SWITCHING



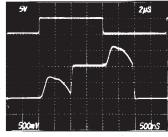
 $R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -500mV$, $V_8 = +500mV$ VOLTAGE = 500mV/DIV $TIME = 1\mu s/DIV$

MUX-08 SMALL-SIGNAL SWITCHING WITH FILTERING



 $R_L = 1M\Omega$, $C_L = 500pF$, $V_1 = 500mV$, $V_8 = +500mV$ VOLTAGE = 500mV/DIV $TIME = 1\mu s/DIV$

MUX-08 SMALL-SIGNAL SWITCHING WITH 2μ8 SAMPLE TIME



MUX-08 SMALL-SIGNAL SWITCHING WITH FILTERING AND 2.5μ8 SAMPLE TIME



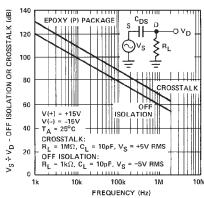
 R_L = 1M Ω , C_L = 500pF, V_1 = -500mV, V_8 = +500mV VOLTAGE = 500mV/DIV TIME = 500ms/DIV

NOTE:

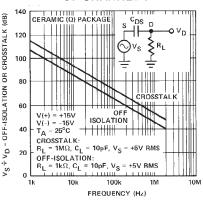
Top waveforms: Digital Input 5V/DIV Bottom waveforms: Multiplexer Output

TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

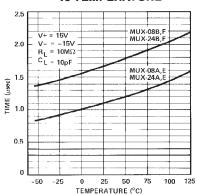
MUX-08 CROSSTALK AND OFF ISOLATION PERFORMANCE OF CHANNEL 8



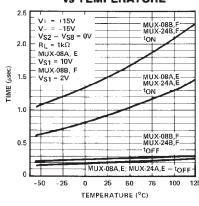
MUX-08 CROSSTALK AND OFF ISOLATION PERFORMANCE OF CHANNEL 8



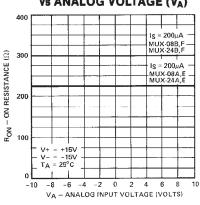
TRANSITION TIMES vs TEMPERATURE



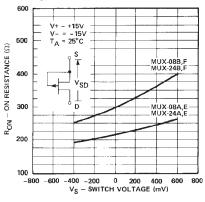
ENABLE DELAY TIMES vs TEMPERATURE



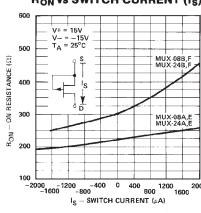
"ON" RESISTANCE (R_{ON}) vs ANALOG VOLTAGE (V_A)



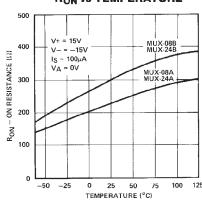
R_{ON} vs SWITCH VOLTAGE (V_{SD})



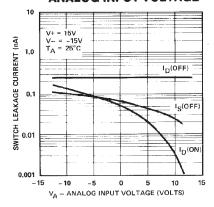
R_{ON} vs SWITCH CURRENT (is)



RON VS TEMPERATURE

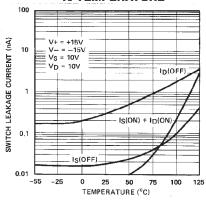


SWITCH LEAKAGE
CURRENTS vs
ANALOG INPUT VOLTAGE

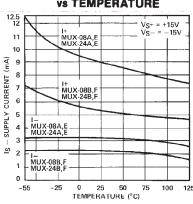


TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

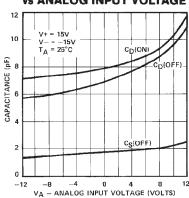
SWITCH LEAKAGE CURRENTS vs TEMPERATURE



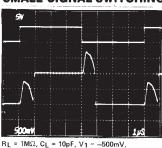
SUPPLY CURRENTS VS TEMPERATURE



MUX-08 SWITCH CAPACITANCES vs Analog input voltage

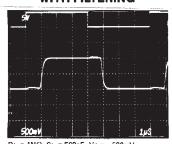


MUX-24 SMALL-SIGNAL SWITCHING



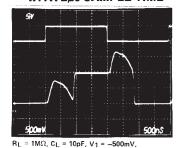
RL = $1M\Omega$, CL = 10pF, $V_1 = -500mV$, $V_4 = +500mV$ VOLTAGE = 500mV/DIV, $TIME = 1\mu s/DIV$

MUX-24 SMALL-SIGNAL SWITCHING WITH FILTERING



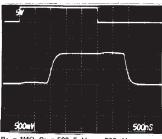
 $R_L = 1M\Omega$, $C_L = 500pF$, $V_1 = -500mV$, $V_4 = +500mV$ VOLTAGE -500mV/DIV, TIME $-1\mu s/DIV$

MUX-24 SMALL-SIGNAL SWITCHING WITH 2µ8 SAMPLE TIME



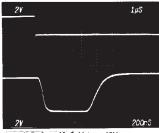
V4 = +500mV V0LTAGE = 500mV/DIV, TIME = 500ns/DIV

MUX-24 SMALL-SIGNAL SWITCHING WITH FILTERING AND 2.5µ8 SAMPLE TIME



R_L = 1MΩ, C_L = 500pF, V₁ = -500mV, V₄ = +500mV VOLTAGE = 500mV/DIV, TIME = 500ns/DIV

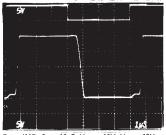
MUX-24 BREAK-BEFORE-MAKE SWITCHING



 $R_L = 1k\Omega$, $C_L = 10pF$, V_1 , $\phi = 10V$ VOLTAGE = 2V/DIV, TIME = 200ns/DIV

-7-

MUX-24 LARGE-SIGNAL SWITCHING



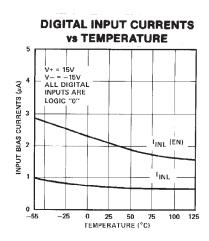
 $R_L = 1M\Omega$, $C_L = 10pF$, $V_1 = -10V$, $V_4 = +10V$ VOLTAGE = 5V/DIV, $TIME = 1\mu s/DIV$

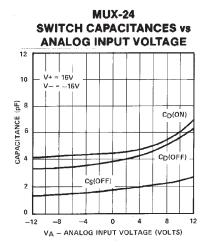
NOTE:

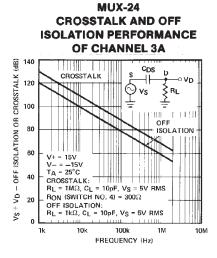
REV. C

Top waveforms: Digital Input 5V/DIV Bottom waveforms: Multiplexer Output

TYPICAL PERFORMANCE CHARACTERISTICS (Applies to all grades, unless otherwise noted.)

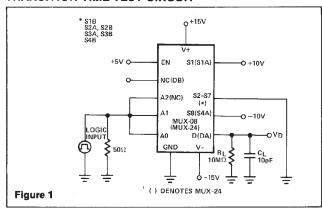




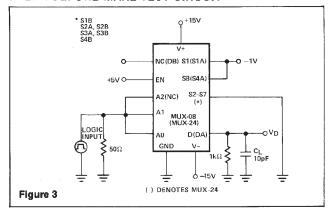


A.C. TEST CIRCUITS

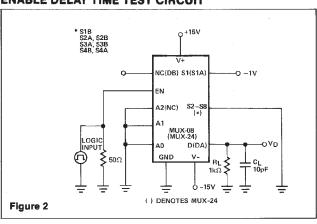
TRANSITION TIME TEST CIRCUIT



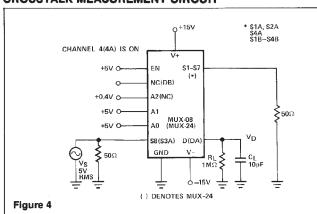
BREAK-BEFORE-MAKE TEST CIRCUIT



ENABLE DELAY TIME TEST CIRCUIT

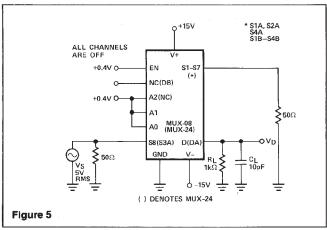


CROSSTALK MEASUREMENT CIRCUIT

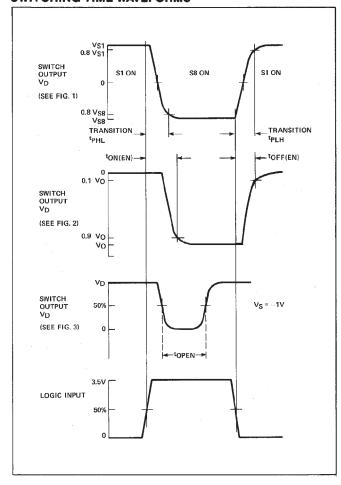


A.C. TEST CIRCUITS

OFF-ISOLATION MEASUREMENT CIRCUIT



SWITCHING TIME WAVEFORMS



APPLICATIONS INFORMATION

These analog multiplexers employ ion-implanted JFETs in a switch configuration designed to assure break-before-make action. The turn-off time is much faster than the turn-on time to guarantee this feature over the full operating temperature and input voltage range. Fabricated with Bipolar-JFET processing, special handling as required with CMOS devices, is not necessary to prevent damage to this multiplexer. Because the digital inputs only require a 2.0V logic "1" input level, power-consuming pull-up resistors are not required for TTL compatibility to insure break-make switching as is most often the case with CMOS multiplexers. The digital inputs utilize PNP input transistors where input current is maximum at the logic "0" level and drops to that of a reverse-biased diode (about 10nA) as the input voltage is raised above ≈ 1.4V.

The "ON" resistance, RON, of the analog switches is constant over the wide input voltage range of -15V to +11V with $V_{SUPPLY} = \pm 15V$. Higher input voltage is tolerable provided that some form of current limiting is employed (such as that of an op-amp output stage) to avoid exceeding junction temperature and power dissipation requirements. For normal operation, however, positive input voltages should be restricted to 11V (or 4V less than the positive supply). This assures that the VGS of an "OFF" switch remains greater than its Vp, and prevents that channel from being falsely turned "ON". When operating with negative input voltages, the gate-tochannel diode will be turned on if the voltage drop across an "ON" switch exceeds -0.6V. While this condition will cause an error in the output, it will not damage the switch. In lab tests, the multiplexer output has been loaded with a $0.01 \mu F$ capacitor in the circuit of Figure 1. With $V_1 = -10 V$ and $V_8 = +10V$, the logic input was driven at a 1kHz rate. The positive-going slew rate was 0.3V/µs which is equivalent to a normal I_{DSS} of 3mA. The negative-going slew rate was $0.7V/\mu s$ which is equivalent to a "reverse" I_{DSS} of 7mA. Note that when switch 1 is first turned "ON" it has a drop of -20V across its terminals. In spite of that fact, the current is limited to approximately twice its normal IDSS.

CROSSTALK AND OFF-ISOLATION

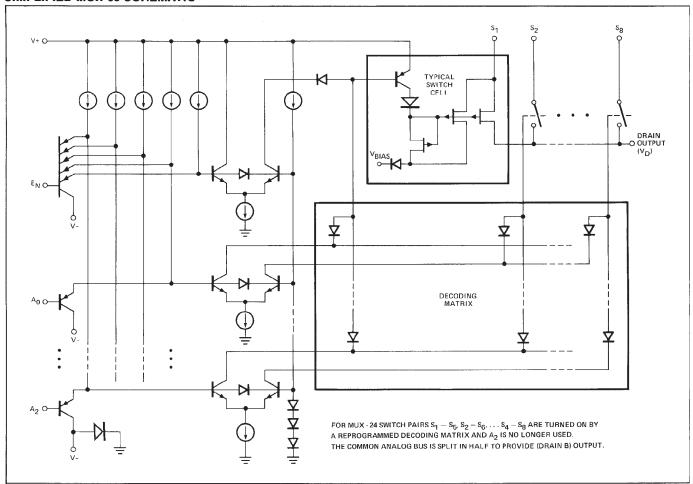
Crosstalk and off-isolation performance is influenced by the type of package selected. Epoxy (P) packaged devices typically exhibit a 12dB improvement in off-isolation (f = 500kHz) performance when compared to ceramic (Q) packaged devices. Epoxy packaged devices typically exhibit a 15dB improvement in crosstalk (f = 500kHz) performance when compared to ceramic (Q) packaged devices.

SINGLE SUPPLY OPERATION OF JFET MULTIPLEXERS

PMI's JFET multiplexers will operate from a single positive supply voltage with the negative supply pin at ground potential. The analog signal range will include ground.

For complete single supply operation information, refer to application note, AN-32.

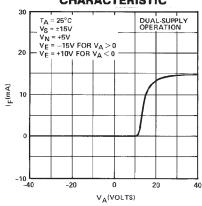
SIMPLIFIED MUX-08 SCHEMATIC



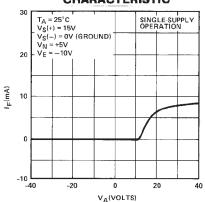
The simplified MUX-08/MUX-24 schematic shows that logic trip points are determined by two forward diode drops. An internal clamping diode between V- and ground prevents excessive current flow between V+ and ground in the event that V- becomes open circuit. The decoding matrix is accomplished by a programmed diode array. The switch cell consists of P channel JFET's with appropriate blocking diodes which ruggedizes the circuit's overvoltage and supply loss characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

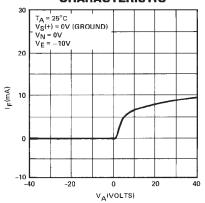
OVERVOLTAGE V-I CHARACTERISTIC



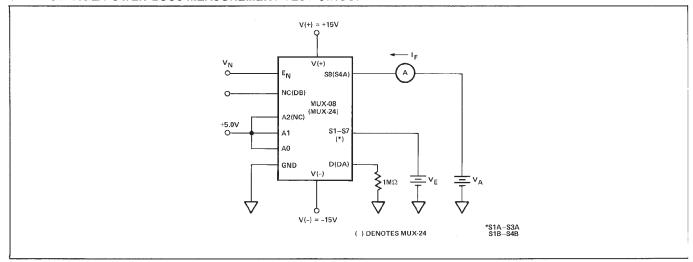
OVERVOLTAGE V-I CHARACTERISTIC



POWER-LOSS V-I CHARACTERISTIC

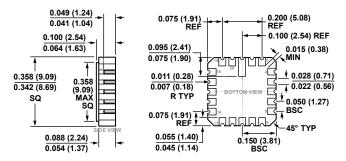


OVERVOLTAGE/POWER-LOSS MEASUREMENT TEST CIRCUIT



MUX-08 Data Sheet

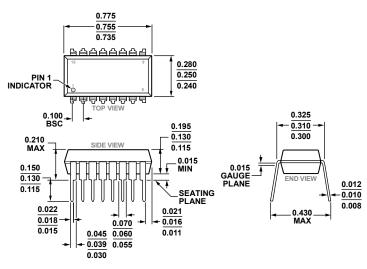
OUTLINE DIMENSIONS



CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETER DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.

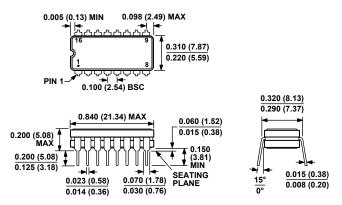
Figure 6. 20-Terminal Ceramic Leadless Chip Carrier [LCC] (E-20-1)

Dimensions shown in inches and (millimeters)



COMPLIANT TO JEDEC STANDARDS MS-001-BB

Figure 7. 16-Lead Plastic Dual In-Line Package [PDIP]
Narrow Body
(N-16)
Dimensions shown in inches

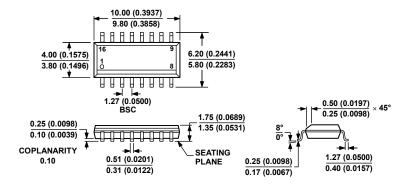


CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETER DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.

Figure 8. 16-Lead Ceramic Dual In-Line Package [CERDIP] (Q-16) Dimensions shown in inches and (millimeters) Rev. C | Page 12 of 14

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Data Sheet MUX-08



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CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.

Figure 9. 16-Lead Standard Small Outline Package [SOIC_N] Narrow Body (R-16)

Dimensions shown in millimeters and (inches)

ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Package Option
MUX08EPZ	0°C to 70°C	16-Lead PDIP	N-16
MUX08EQ	−25°C to +85°C	16-Lead CERDIP	Q-16
MUX08FPZ	-40°C to +85°C	16-Lead PDIP	N-16
MUX08FQ	−25°C to +85°C	16-Lead CERDIP	Q-16
MUX08FSZ	-40°C to +85°C	16-Lead SOIC_N	R-16
MUX08NBC	25°C	DIE	
5962-8771601EA	−55°C to +125°C	16-Lead CERDIP	Q-16
5962-87716022A	−55°C to +125°C	20-Terminal Ceramic LCC	E-20-1
5962-8771602EA	−55°C to +125°C	16-Lead CERDIP	Q-16
MUX08AQ/883C	−55°C to +125°C	16-Lead CERDIP	Q-16
MUX08BQ/883C	−55°C to +125°C	16-Lead CERDIP	Q-16

¹ Z = RoHS Compliant Part

MUX-08 Data Sheet

REVISION HISTORY

5/2019—Rev. B to Rev C
Obsoleted MUX-24 and MUX08BRC/883Universal
Deleted MUX-24 Functional Diagram
Changes to Features Section, Ordering information Section, and
General Description Section
Changed MUX-08A/E MUX-24A/E Column to MUX-08A/E
Column, Electrical Characteristics Table and MUX-08B/F
MUX-24B/F Column to MUX-08B/F Column, Electrical
Characteristics Table
Changed MUX-08A/MUX-24A Column to MUX-08A Column
and MUX-08B/MUX-24B Column to MUX-08B Column,

Electrical Characteristics Table, and MUX-08E/MUX-24E Columbia	umn
to MUX-08E Column and MUX-08F/MUX-24F Column to	
MUX-08F Column, Electrical Characteristics Table	3
Change to "ON" Resistance Parameter, MUX-08A	3
Deleted MUX-24 Dice Characteristics	4
Deleted MUX-24 Logic State Table	5
Deleted Differential Multiplexers and Figure 6	10
Added Outlines Dimension Section	12
Added Ordering Guide	13

ANALOGDEVICES

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